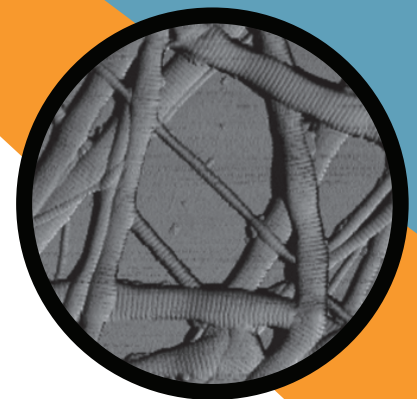
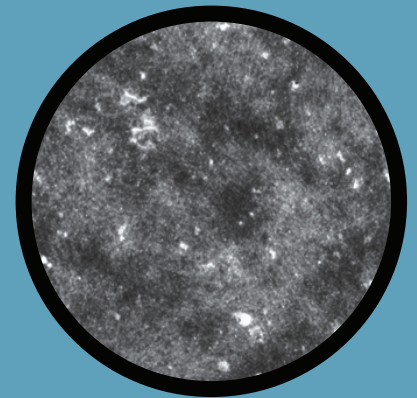


# Scanning Ion Conductance and Atomic Force Microscopy for Live Cell Imaging

Scanning Ion Conductance Microscopy (SICM) enables non-invasive in-liquid imaging of cellular and sub-cellular structures with high accuracy and reliability. A glass micropipette used for the probe in SICM, instead of a silicon based stylus in AFM, can glide over live cells while maintaining an absolute non-contact imaging mode.



**Monday May 13th, 2013**  
**11:00 am in Forchheimer 614**

**Speaker: Brian Choi**  
**Research Product Manager**  
**Park Systems**

**Hosted by the Analytical Imaging Facility**  
Contact Frank Macaluso with any questions  
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